

10071881

PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10071881	02/08/2002	250	311	2881	Fernandez

**APPLICANTS: Hosokawa Fumio; Nagayama Kuniaki; Danev Radostin;

**CONTINUING DATA VERIFIED:

None KF

** FOREIGN APPLICATIONS VERIFIED:
JAPAN 2001-033799 02/09/2001 KF

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	ATTORNEY DOCKET NO
Foreign priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no			116-020155
35 USC 119 conditions met <input type="checkbox"/> yes <input checked="" type="checkbox"/> no			
Verified and Acknowledged Examiners's initials KF			

TITLE : Lens system for phase plate for transmission electron microscope and transmission electron microscope

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
Assistant Examiner		Total Claims	Print Claim for O.G.
Primary Examiner		DRAWING	
PREPARED FOR ISSUE		Sheets Drawn	Figs Drawn
Application Examiner		Print Fee	
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